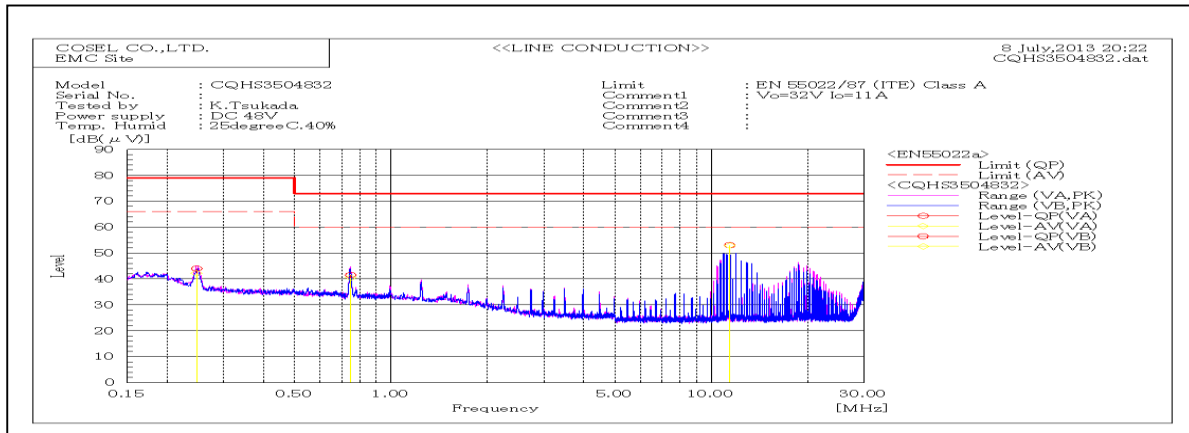
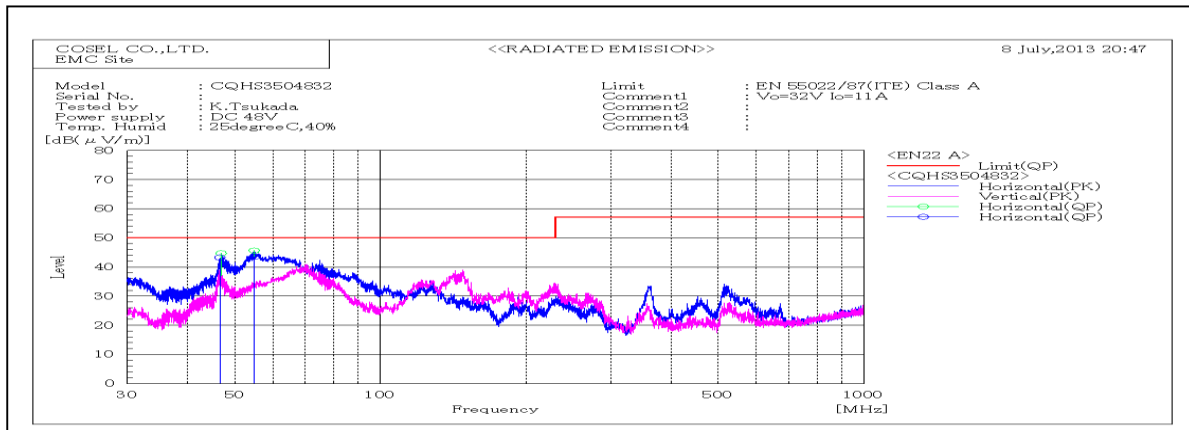


DATA SHEET		Date	08-Jul-13
Model	CQHS3504832	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Tsukada



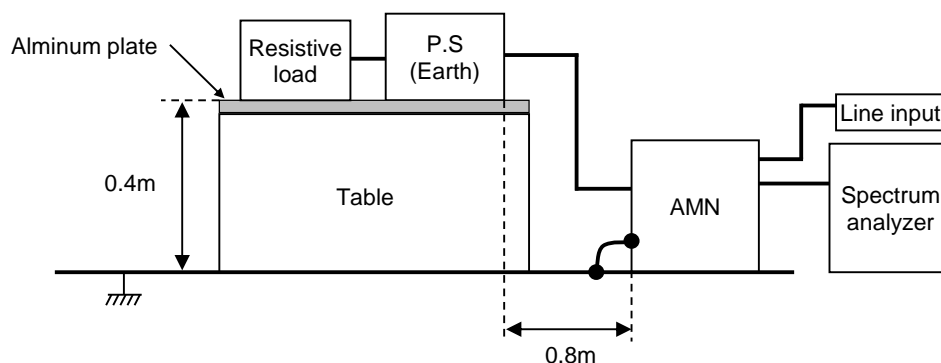
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.24684		VA	23.9	22.1	20.1	44	42.2	79	66	35	23.8	Pass	
0.74773		VA	21.5	20.5	20	41.5	40.5	73	60	31.5	19.5	Pass	
11.439		VB	32.4	20.6	20.6	53	52.9	73	60	20	7.1	Pass	



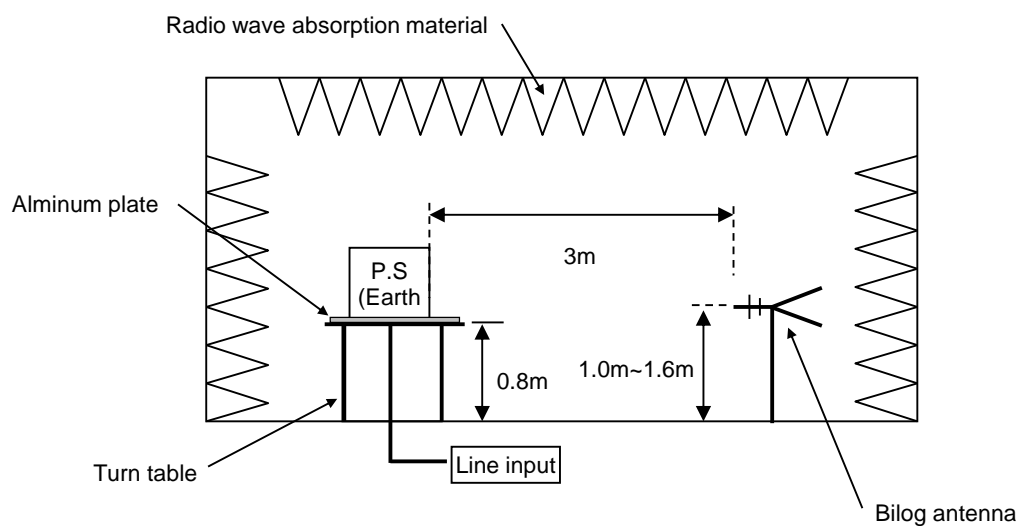
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
46.575	H	Stable	65.5	-22.3	43.2	50	6.8	Pass	103	202		
55.013	H	Stable	67.6	-24	43.6	50	6.4	Pass	103	229		

DATA SHEET		Date	08-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Tsukada

1. Line conduction



2. Radiated emission

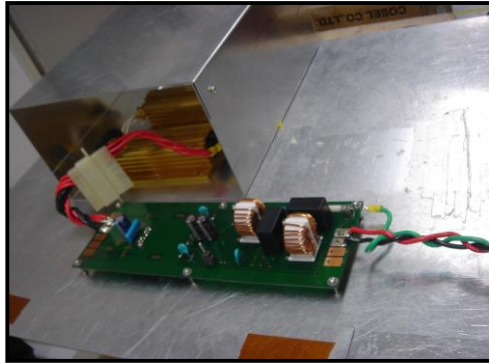


Test: EMI

Model Name: CQHS350 Series

○ Photographs of Test Set-Up

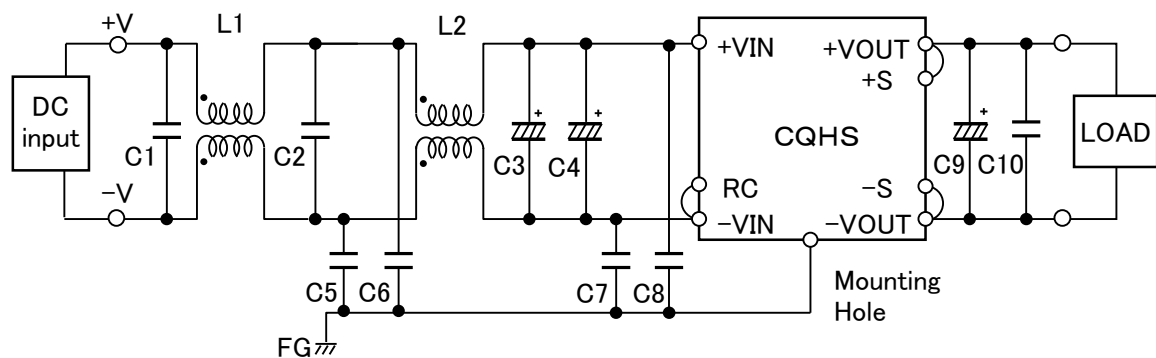
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1, L2 : 0.5mH 15A Inductor (SC-15-05J NEC TOKIN)
- C1, C2 : 310V 2.2μ F Film capacitor (OKAYA ELEC)
- C3, C4 : 100V 68μ F Electlic capacitor (LXV NIPPON CHEMI-CON)
- C5, C6, C7, C8 : 250V 4700pF Ceramic capacitor (Type KY MURATA)
- C9 : CQHS3504832 50V 470μ F Electlic capacitor (LXZ NIPPON CHEMI-CON)
- C10 : CQHS3504850 80V 330μ F Electlic capacitor (KY NIPPON CHEMI-CON)
- C10 : 100V 0.1μ F Film capacitor (Nitsuko)